

國立東華大學應用數學系
專題演講

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講題：On the Monitoring of Simple Linear Berkson Profiles

時間：100年3月18日(星期五) 15:10-16:40

摘要

In some applications, the quality of a process or product is better characterized and summarized by a functional relationship between a response variable and one or more explanatory variables. Profile monitoring is used to understand and to check the stability of this relationship or curve over time. We consider the quality of a process which can be characterized by a simple linear Berkson profile. Some existing approaches for monitoring the simple linear profile and several new proposed schemes are studied for charting the simple linear Berkson profile. Simulation studies demonstrate the effectiveness and efficiency of the proposed monitoring schemes. Additionally, a systematic diagnostic approach is provided to spot the changepoint location of the process and to identify the parameter of change in the profile. Finally, an example from semiconductor manufacturing is used to illustrate the implementation of the proposed monitoring scheme and diagnostic approach.



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